



THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: KOMURA et al.

Serial No.: 09/616,372

Filed: 7/13/2000

Title: METHOD FOR MEASURING  
THICKNESS OF OXIDE FILM

Atty. Dkt.: 01-50

Art Unit: 2881

Examiner: Souw

**Mail Stop AF**

Commissioner for Patents  
U.S. Patent and Trademark Office  
2011 South Clark Place  
Crystal Plaza Two, Lobby, Room 1B03  
Arlington, VA 22202

Date: 26 March 2004

**AMENDMENT UNDER 37 CFR 1.116**

Sir:

In response to the office action mailed 5 December 2003, please amend the application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims that begins on page 4 of this paper.

**Remarks** begin on page 10 of this paper.